

Model: STT-700(X), supports 13 or 26slots, floating ground structure, and allows any module put in any slot for flexible configuration. Can configure up to 416 VI channels and 256 digital pins.

Software: Visual C++, supports both True Parallel and Index Parallel test modes.

Analog/Mixed-signal IC test modules

Module	Voltage/Current range	Channel number	Voltage Accuracy	Current Accuracy
FOVI	±50V/300mA /1A Pulse	8(4 groups)	±(0.35mV+0.025%Rdg)	±(3nA+0.05%Rdg)
FPVI120	±100V/±2A /±20A pulse	2	±(0.35mV+0.025%Rdg)	±(20nA+0.05%Rdg)
FVII1000	±1000V/10mA	2	±(0.1V+0.1%Rdg)	±(20nA+0.1%Rdg)
FVII16	±40V/100mA	16	±(0.7mV+0.025%Rdg)	±(10nA+0.5%Rdg)
OMS	±(200V,20V,10V,5V,2V,1V,100mV)	8	±(0.1mV+0.01%Rdg), eight channels voltage meter module	
QTMU	±7.5V, ±52V,	4	20Mhz (Bandwidth) , 100Mhz (Counter)	
DIO32	0V-6V, 40mA(PMU)	16 IO/ 16 OUT	33Mhz, 4M memory depth, 10ns pulse width	
PAM	1nA	1	Minimum current measurement: 10pA	

remark: VI modules equipped with patented real-time accuracy self-checking on the board feature to prevent test escape.

Discrete device test modules

Module	Specifications	Accuracy	Digitizer	Remark
DDC1230/E	3 channels(D/G/S), ±1400V/30A/100A	<0.1mOhm <2nA	500Khz	One module can finish single mosfet DC test
DDC2K200	3 channels(D/G/S), ±2000V/200A	<0.1mOhm <2nA	500Khz	One module can finish single mosfet DC test
UIL10090FN	3 channels(D/G/S), ±1400V/200A	1% voltage 1% current	2Mhz	Inductive load 0.01mH ~ 160mH, step 10uH
UIL3K200	3 channels(D/G/S), ±3000V/200A	1% voltage 1% current	2Mhz	Inductive load 0.01mH ~ 160Mh, step 10uH
DVSD120	±120V/50A/200mS	1% force current, 0.1% voltage	666Khz	Max power: 2400W
QG17100	±1700V/100A	1nC	2Mhz	Resolution 0.02nC
SW12400	±1200V/400A/1000A(Isc)	0.25ns	Switching test box, with external 4G oscilloscope	
LCR module	1 channel	0.1mOhm 0.01Pf / 0.1uH		Similar as E49**A

Digital module

	specifications	Channels	remark
DPU32	50Mhz/100Mhz vector rate 64M memory depth per pin -1.5V to 6.5V	32	PMU per pin NRZ/RO/RZ/SBC/HiZ 64 Timing sets with 4 phases, 4 windows